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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Examiner: Johnston, Phillip A.

David L. Adler, et al.

Serial No. 10/017,262

Art Unit: 2881

Filing Date: 12/14/2001

Attorney Docket No.: P960 (11.700)

Title: Photoelectron Emission Microscope for Wafer and Reticle Inspection

Honorable Commissioner of Patents
Washington, D.C. 20231

TECHNOLOGY CENTER 2800

RECEIVED

APR 17 2003

Sir:

AMENDMENT AND RESPONSE

This Amendment and Response is responsive to the Office Action mailed on November 6, 2002. Payment for the two month extension fee is included herewith.

The amendments herein are set forth in accordance with the revised format of amendments per the Off. Gaz. Pat. Office (February 25, 2003).

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